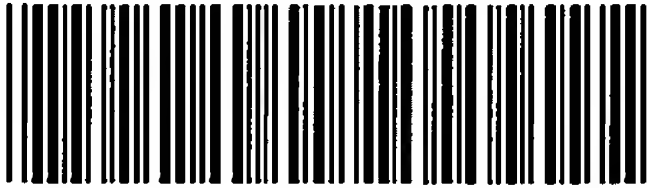


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/647,224	SEKI, HIROSHI	
	Examiner	Art Unit	
	Joseph Chang	2817	

SEARCHED			
Class	Subclass	Date	Examiner
331	108A,158 116FE,	2/9/2005	JC
331	116R,160		
331	107A,108d		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST(attached)	2/9/2005	JC